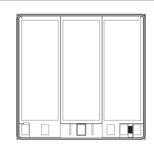
650 V, 300 A Field Stop Trench IGBT with Solderable Top Metal



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Features

- AEC–Q101 Qualified
- Maximum Junction Temperature 175°C
- Positive Temperature Coefficient
- Easy Paralleling
- Short Circuit Rated
- Very Low Saturation Voltage: VCE(SAT) = 1.5 V (Typ.) @ IC = 300 A
- Optimized For Motor Control Applications
- Integrated Temp Sensor And Current Sensor
- Emitter Pad Covered With Solderable Metal Layer

Applications

- Automotive Traction modules
- General Power Modules

ORDERING INFORMATION

Part Number	PCGA300T65DF8M1					
Packing	Water (sawn on foil)					
	mils	μm				
Die Size	472×472	12,000 × 12,000				
Emitter Attach Area	3 × (141 × 383)	3 × (3,580 × 9,720)				
Gate / Sensor Pad Attach Area	6 × (27 × 39)	6 × (680 × 980)				
Die Thickness	3 78					
Top Metal	5 um AlSiCu + 1.15 um Ti/NiV/Ag (STM)					
Back Metal	0.65 um NiV/Ag					
Topside Passivation	Silicon Nitride plus Polyimide					
Wafer Diameter	200 mm					
Max Possible Die Per Wafer	136					

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ABSOLUTE MAXIMUM RATINGS (T_{VJ} = 25°C unless otherwise noted)

Parameter	Symbol	Ratings	Units
Collector-Emitter Voltage	V _{CES}	650	V
Gate-Emitter Voltage	V _{GES}	±20	V
DC Collector Current, limited by T _{VJ} max	Ιc	(Note 1)	А
Pulsed Collector Current, V_{GE} =15 V, tp limited by T_{VJ} max (Note 2)	I _{CM}	900	А
Short Circuit Withstand Time, V_{GE} = 15 V, V _{CE} \leq 400 V, T _{VJ} \leq 150 $^{\circ}$ C	t _{sc}	5	μs
Operating Junction Temperature	T _{VJ}	-40 to +175	°C
Storage Temperature Range	Tstg	+17 to +25	°C

1. Depends on the thermal properties of assembly

2. Not subject to production test - verified by design/characterization

ELECTRICAL CHARACTERISTICS OF THE IGBT (T_{VJ} = 25°C unless otherwise noted)

Parameter	Symbol	Test Condition	Min.	Тур.	Max.	Units
Static Characteristics (Tested on wafers)						
Collector-Emitter Breakdown Voltage	BV _{CES}	$V_{GE} = 0 V, I_C = 1 mA$	650	-	-	V
Collector-Emitter Saturation Voltage	V _{CE(SAT)}	I _C = 100 A, V _{GE} = 15 V	-	1.25	1.55	V
Gate-Emitter Threshold Voltage	V _{GE(th)}	V_{GE} = V_{CE} , I_C = 300 mA	4.5	5.5	6.5	V
Collector Cut-Off Current	I _{CES}	$V_{CE} = V_{CES}, V_{GE} = 0 V$	-	-	40	μA
Gate Leakage Current	I _{GES}	$V_{GE} = V_{GES}, V_{CE} = 0 V$	-	-	±400	nA
On-chip temperature – sense diode voltage	V _F	I _F = 0.5 mA	2.0	2.4	2.8	V

Integrated Temp and Current Sensor Characteristics

(not subjected to production test - verified by design / characterization)

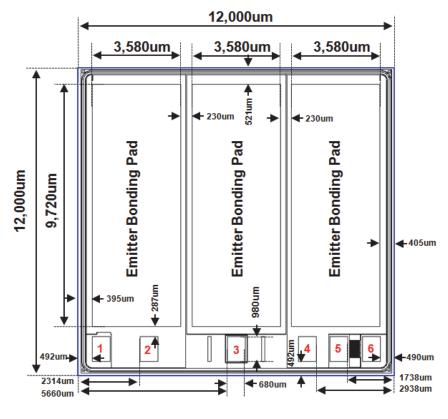
On-chip temperature-sense diode voltage	V _F	I_F = 0.5 mA, T_{VJ} = 100 $^\circ\text{C}$	-	1.9	_	V
Emitter Sense Area Ratio	βarea	Sense Area/Total Area		1/10K		-
Emitter Current Sense Ratio	β10Ω	I_{CE} = 300 A, V_{GE} = 15 V R_{SENSE} = 10 Ω	-	18K	-	-

Electrical Characteristics (Not subjected to production test - verified by design/characterization)

Collector to Emitter Saturation Voltage	V _{GE} = 15 V	T_{VJ} = 25 °C	-	1.5	1.9	V	
		v _{GE} = 15 v	T_{VJ} = 175 °C	-	1.8	-	V
Input Capacitance	C _{IES}			-	14.0	-	nF
Output Capacitance	C _{OES}	V _{CE} = 30 V, V _C f = 1 MHz	_{AE} = 0 V		690		pF
Reverse Transfer Capacitance	C _{RES}				106	-	pF
Internal Gate Resistance	R _G	f = 1 MHz		-	1.7	-	Ω
Total Gate Charge	Q _{G(Total)}	V _{CE} = 400 V, I _C = 300 A V _{GE} = 15 V			307	-	nC
Gate-to-Emitter Charge	Q _{GE}			-	97	-	nC
Gate-to-Collector Charge	Q _{GC}			-	64	-	nC
Turn-On Delay Time	t _{d(on)}	V _{CE} = 300 V, I	V _{CE} = 300 V, I _C = 300 A	-	167	-	ns
Rise Time	t _r	$R_G = 15 \Omega$ $V_{GE} = 15 V$ Inductive Load	-	107	-	ns	
Turn-Off Delay Time	t _{d(off)}		-	298	-	ns	
Fall Time	t _f	T _{VJ} = 25 °C		-	38	-	ns

Turn-On Delay Time	t _{d(on)}	V _{CE} = 300 V, I _C = 300 A	-	130	-	ns
Rise Time	t _r	$R_G = 15 \Omega$ V _{GE} = 15 V	-	93	-	ns
Turn-Off Delay Time	t _{d(off)}	Inductive Load	-	395	-	ns
Fall Time	t _f	T _{VJ} = 150 °C	-	78	-	ns

3. For ordering, technique and other information on Onsemi automotive bare die products, please contact automotivebaredie@onsemi.com



- 1. Current Sense Bonding Pad
- 2. Emitter Sense Bonding Pad
- 3. Gate Bonding Pad
- 4. Emitter Sense Bonding Pad
- 5. Temp Sense Anode Bonding Pad
- 6. Temp Sense Cathode Bonding Pad

Figure 1. Dimensional Outline and Pad Layout

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